Posters

1. Variability-aware Compact Modeling of Nano-scale Technologies with Customized Test Structure Designs
   Ying Qiao and Costas J. Spanos, Dept. of EECS, UC Berkeley, Berkeley, CA, USA 94720

2. Statistical Static Timing Analysis Based on Current Source Modeling of ASIC Gates
   Tiansong Cui, Yanzhi Wang, Shahin Nazarian, and Massoud Pedram (USC)

3. Statistical Observation of NBTI and PBTI Degradations
   Hiromitsu Awano, Masayuki Hiromoto and Takashi Sato, Graduate School of Informatics, Kyoto University, Yoshida-hon-machi, Sakyo, Kyoto, 606-8501 Japan

4. NBTI Characterization Using Pulse-Width Modulation
   Ryo Harada, Masanori Hashimoto, and Takao Onoye, Dept. Information Systems Engineering, Osaka University

5. Self Aligned Double Patterning Aware Pin Access and Standard Cell Layout Co-Optimization
   Xiaoqing Xu, Brian Cline*, Greg Yeric*, Bei Yu, David Z. Pan, ECE Department, University of Texas at Austin, Austin, USA, *ARM Inc, Austin, USA

6. Design for Manufacturing with Triple Patterning Lithography
   Bei Yu, Xiaoqing Xu, Jhih-Rong Gao, David Z. Pan, ECE Department, University of Texas at Austin, Austin, USA

7. Process Variation Mitigation in Next Generation Lithography
   Yuelin Du, Zigang Xiao, Haitong Tian and Martin D. F. Wong, University of Illinois at Urbana-Champaign

8. Rapid Exploration of Processing & Design Guidelines to Overcome Carbon Nanotube Variations
   Gage Hills, Chi-Shuen Lee, H.-S. Phillip Wong, Subhasish Mitra, Stanford University

   Ying-Yu Chen, Amit Sangai, Morteza Gholipour, and Deming Chen, Department of Electrical and Computer Engineering, University of Illinois at Urbana-Champaign

10. An AC-mode HCI Model and Output Power Management Scheme for Millimeter-wave PAs
    Rui Wu, Kenichi Okada, and Akira Matsuzawa, Department of Physical Electronics, Tokyo Institute of Technology

11. Detailed Study of Ring Oscillator Stability and its Improvement Methodology
    T. Okagaki, T. Tsutsui, M. Fujii, A. Tsuda, K. Shibutani, M. Yokota and K. Onozawa
    Renesas Electronics Corp., 4-1 Mizuhara Itami, Hyogo 664-0005, Japan

12. Variability Analysis of a 28nm Near-Threshold Synchronous Voltage Converter
    Temesghen Tekeste, Ayman Shabra, *Duane Boning, Ibrahim (Abe) M. Elfadel, Masdar Institute of Science and Technology, *Massachusetts Institute of Technology

13. Measurement of Channel Length Variability
    K. Terada and K. Tsuji, Hiroshima City University
   Masashi Imai, Hirosaki University and Tomohiro Yoneda, National Institute of Informatics

15. High Sigma Variability Modeling of TG Latches
   Il-Joon Kim, Wael M. Elsharkasy, Ahmed M. Eltawil, Fadi Kurdahi, and Amin Khajeh*,
   Electrical Engineering and Computer Science Department, University of California,
   Irvine, Irvine, CA, *Intel Labs, Hillsboro, Oregon, USA

16. Statistical Characteristics Analysis of “N-curve” and Static Noise Margin for Yield Prediction of SRAM Cells
   T. Mizutani1, Y. Yamamoto2, H. Makiyama2, H. Shinohara2, T. Iwamatsu2, H. Oda2, S.
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